

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/618,302	HONKEN ET AL.
Examiner	Art Unit	
Syed Zaidi	2616	

SEARCHED

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	12/6/2007	SZ
Inventor :HONKEN ET AL.	12/6/2007	SZ
(IEEE Xplore Database(http://ieeexplore.ieee.org/Xplore/DynWel.jsp)	12/6/2007	SZ
(370/516 370/498 370/496).CCLS (375/362).CCLS.	12/6/2007	SZ
Consulted with SPE Seema Rao	12/6/2007	SZ

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner